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Detection Limits And
Recoveries For

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Analysis of Trace Elements on Wafer Surfaces for ...

Inductively Coupled Plasma
Mass Spectrometry Mass
spectrometry (MS) is an
analytical technique that
ionizes chemical species and
sorts the ions based on

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their mass-to-charge ratio.
Inductively coupled plasma
mass spectrometry (ICP-MS)
is a type of mass
spectrometry which is
capable of detecting metals
and several non-metals at

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Applications of ICP-MS - Agilent

Inductively coupled plasma mass spectrometry (ICP-MS) is a type of mass spectrometry that uses an Inductively coupled plasma to ionize the sample. It

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atomizes the sample and creates atomic and small polyatomic ions, which are then detected. It is known and used for its ability to detect metals and several non-metals in liquid samples at very low concentrations.

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EPA Method 200.8: Determination of Trace Elements in ...

The WSMS system constitutes an enhancement of the WSPS series and combines VPD technology with the

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outstanding detection limits of the WSPS series with a fully integrated ICP-MS.. Advantages at a glance: All media, from the chemicals for VPD to calibration of the ICP-MS, are provided fully automatically by the

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Can VPD/SME-ICP-MS Analysis Ever Be Made Routine?

inductively coupled plasma
mass spectrometry (VPD-ICP-
MS). APPLICATION NOTE 43359
Goal To determine ultratrace

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metal concentrations in semiconductor silicon wafer vapor phase decomposition (VPD) samples use cold plasma and triple quadrupole technologies to reduce background equivalent concentrations (BEC) and

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This technique, VPD ICP-MS provides accurate measurement of up to 60 elements and detection

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limits of in the range of $1E6-E10$ atoms/sq.cm on the silicon wafer. Related Techniques [edit] One related technique is VPD-DC (vapour phase decomposition-droplet collection), where the wafer is scanned with a

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droplet that collects the metal ions that were dissolved in the decomposition step.

Inductively Coupled Plasma Mass Spectrometry (ICP-MS)

1.9 This method should be

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used by analysts experienced in the use of inductively coupled plasma mass spectrometry (ICP-MS), the interpretation of spectral and matrix interferences and procedures for their correction. A minimum of six

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months experience with commercial instrumentation is recommended.

Application of vapor phase decomposition techniques (VPD ...

Can VPD/SME-ICP-MS ... SME

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provides a fast and reliable
method for the extraction of
trace ... Oxide Metals
Characterization by Surface
Metals Extraction
Inductively Coupled Plasma
Mass Spectrometry (SME-ICP-
MS), Semiconductor

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International, July 2000,
Vol 34, p 217 0 20 40 60 80
100 120

Metrology Systems VPD | PVA TePla MPS

Inductively coupled plasma
mass spectrometry (ICP-MS)

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analysis of the resulting liquid sample is a direct approach for measuring the cleanliness of production processes run in the wafer fab. Required analytical measurements at $<10^8$ atoms cm^{-2} have forced the need

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for lower detection limits,
lower instrument background,
higher sensitivity and well-
controlled analytical blanks
in VPD-ICP-MS ...

**Inductively coupled plasma
mass spectrometry -**

Acces PDF Vpd Icp Ms Method Detection Limits And Recoveries For **Wikipedia**

The importance of metal contamination in semiconductor processing and the ultimate yield effects has long been understood in the fab. One particular method used to measure

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metallic contamination is Vapor Phase Decomposition (VPD) in combination with Inductively Coupled Plasma Mass Spectrometry (ICP-MS). With this technique low detection limits (10^7 atoms/cm²) can be

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obtained for metals across

...

PUB0099 Significance of VPD ICP-MS Edge Exclusion | Balazs ...

late 1980s, Agilent has
developed ICP-MS systems and

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applications that help to address the challenges of this fast-moving industry. From off-axis ion lenses and cool plasma to the unique, high-sensitivity 8900 ICP-QQQ with MS/MS operation, Agilent has been at the

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forefront of the key ICP-MS innovations critical to the industry.

Vapour phase decomposition - Wikipedia

In this technique the entire oxide layer of the wafer is

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decomposed and concentrated into a single droplet, which then can be measured by inductively coupled plasma mass spectrometry (ICP-MS). Pairing the VPD wafer preparation with ICP-MS analysis gives fab engineers

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increased sensitivity and
lowers detection limits
(into the mid E07 atoms/cm²?
for most elements on a 300
mm silicon wafer).

**E04500 - SEMI E45 - Test
Method for the Determination**

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Due to the difference in metal element detection, the lower detection limit for ICP-MS can extend to parts per trillion (ppt), where the lower limit for ICP-OES is parts per billion (ppb).

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Obviously, if the elements for detection have regulatory limits that are below or near the lower detection limit of ICP-OES, ICP-MS is the instrument of choice.

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**Determination of Ultratrace
Elements on Silicon Wafer**

...

Figure 1. Detection limits of TXRF, VPD-ICP-MS, VPD-TXRF and SR-TXRF on 200 mm Si wafer. (DL's for TXRF are based on the instrument

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detection limits from
Atomika; DL's for VPD-ICP-MS
are based on the routinely
reporting detection limits
from Balazs Analytical Lab;
DL's for VPD-TXRF are based
on the

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**Using VPD ICP-MS to monitor
trace metals on unpatterned**

...

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The method has yielded good
results for the detection
and measurement of nickel
and iron. To improve the

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range of elemental impurities and lower detection limits, the acid droplets obtained from the silicon wafers are analyzed by ICP-MS (Inductively coupled plasma mass spectrometry) .

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Procedure for Measuring the Concentration of Palladium

The inorganic contamination on silicon wafer surfaces is collected by VPD. To quantify Ca and Fe, VPD/TXRF is used due to its

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sufficiently low detection limits. Na and Cu are quantified by VPD/GFAAS or VPD/ICP-MS. All analytical methods are widely used for the characterization of surface cleanliness.

Referenced SEMI Standards

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Wafer Preparation | Trace Metal | Vapor Phase ...

ICP-MS is an important analytical tool for the semiconductor industry. 7
This sensitive, rapid, multielement atomic

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spectroscopic technique offers ultralow detection capability, high sample throughput, wide dynamic range, wide elemental coverage, rapid semiquantitative analysis, and the ability to provide

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isotopic information. 8 With its relatively simple spectrum, the spectrometer is rugged ...

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In this study, only Na, Al,

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Fe and Zn Table 1 Detection
limits of 9 elements by
VPD/GFAAS and VPD/HR ICP-MS
GFAAS Lowest detectable HR
ICP-MS Lowest detectable
Elements instrument surface
concentration instrument
surface concentration

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detection limits by GFAAS					
detection limits by HR ICP-MS (ppb)	(X 101atoms/cmz)				
(ppb)	(X101atoms/cm`)			Sodium	
0.1	0.8	0.06	0.5	Aluminum	
0.2	1.4	0.05	0.4	Calcium	0
...					

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Improving the detection limits for vapor phase ...

Dilute the digestate and
make up to 1 to 2 % v/v
nitric acid for ICP-MS
measurement. I always
recommend that the analyst
perform a method validation

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study with any new or revised procedure. Please let me know if you have any questions.

Comparison of ICP-OES and ICP-MS for Trace Element ...

VPD ICP-MS (Vapor Phase

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Decomposition followed by ICP-MS analysis) is an analytical technique gaining momentum as an important method used to measure trace metal surface contamination on wafer surfaces.

Historically, TXRF has been

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used to analyze surface metal contamination since many facilities have TXRF equipment available in-house, providing quick results.

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